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1: # -----
2: # File testplan.tpl
3: # -----
4: Version 1.0;
5:
6: # Imports of OTPL sources
7: Import OASISResources.rsc;
8: Import testcondition.tcg;
9: Import asicbins.bdefs;
10:
11: Import DatalogSetupTest.ph;
12: Import FunctionalTest.ph;
13: Import SearchTest.ph;
14: Import DCParametricPowerSupplyTest.ph;
15: Import DCParametricPMUTest.ph;
16:
17: # Import of Runtime files
18: Import pindesc.pin;
19:
20: #-----
21: # Start of the test plan
22: #-----
23:
24: # Name of the TestPlan
25: TestPlan testplan;
26:
27: # The type of DUT
28: DUTType "DiagPB";
29:
30: # This block defines Pattern Lists file-qualified names and
31: # Pattern List variables that are used in Test declarations.
32: # The file-qualified names refer to pattern lists in the named
33: # files. The variables refer to String variables which will
34: # hold the pattern list names at run time. User defined
35: # Flowable objects could set the values of these variables
36: # through an API provided by OASIS.
37: #PListDefs
38: #{
39: #   # File qualified pattern list names
40: #   pattern.plist:DiagPBPat,
41: #   wireModel_fixedCycle.plist:wireModel_fixedCycle,
42: #   wireModel_Alpg.plist:wireModel_PLlist_AlpgTiming,
43: #   wireModel_Scan.plist:wireModel_PLlist_ScanTiming
44: #}
45:
46:
47: # SocketDef, UserVars declaration as before ...
48: SocketDef = socket.soc;
49:
50: # Offline configuration file
51: OfflineDef = offline.cfg;
52:
53: # Declarations of TestConditions TC1Min, TC1Typ, TC1Max,
54: # TC2Min, TC2Typ, TC2Max as before ...

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55: TestCondition TC1Min
56: {
57:     TestConditionGroup = DiagPBTCG;
58:     Selector = min;
59: }
60:
61: TestCondition TC1Max
62: {
63:     TestConditionGroup = DiagPBTCG;
64:     Selector = max;
65: }
66:
67: TestCondition TC1Typ
68: {
69:     TestConditionGroup = DiagPBTCG;
70:     Selector = typ;
71: }
72:
73: TestCondition TC1LevelMin
74: {
75:     TestConditionGroup = DiagPBTCG_Level;
76:     Selector = min;
77: }
78:
79: TestCondition TC1TimingMax
80: {
81:     TestConditionGroup = DiagPBTCG_Timing;
82:     Selector = max;
83: }
84:
85: TestCondition RoffSeq
86: {
87:     TestConditionGroup = RoffSeqCondition;
88: }
89:
90: #
91: # Test condition for Vdd Short test
92: #-----
93: TestCondition Idd_Short_Levels
94: {
95:     TestConditionGroup = wireModel_Vdd_Short_Levels;
96: }
97: TestCondition Idd_Short_DCParams
98: {
99:     TestConditionGroup = wireModel_Vdd_Short_DCParam;
100: }
101:
102: #
103: # Test condition for Open Test
104: #-----
105: TestCondition Contact_Open_Levels
106: {
107:     TestConditionGroup = wireModel_Open_Levels;
108: }

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109: TestCondition Contact_Open_DCPARAMS
110: {
111:     TestConditionGroup = wireModel_Open_DCPARAMS;
112: }
113:
114: #
115: # Test condition for Input Leakage Low test
116: #-----
117: TestCondition Input_Leakage_Low_Levels
118: {
119:     TestConditionGroup = wireModel_Leakage_Levels;
120:     Selector = iil;
121: }
122: TestCondition Input_Leakage_Low_DCPARAMS
123: {
124:     TestConditionGroup = wireModel_Leakage_DCPARAMS;
125:     Selector = vinl;
126: }
127:
128: #
129: # Test condition for Idd static vdd_max test
130: #-----
131: TestCondition Idd_Static_Levels_Max
132: {
133:     TestConditionGroup = wireModel_Idd_Levels;
134:     Selector = max;
135: }
136: TestCondition Idd_Static_DCPARAMS_Max
137: {
138:     TestConditionGroup = wireModel_Idd_DCPARAMS;
139:     Selector = max;
140: }
141:
142: # Minimum Voltage Group
143: #-----
144: TestCondition Func_Min_Dps
145: {
146:     TestConditionGroup = wireModel_Func_Dps_Levels;
147:     Selector = vmin;
148: }
149: TestCondition Func_Min_Sig_VT
150: {
151:     TestConditionGroup = wireModel_Func_SDR_VT_Levels;
152:     Selector = vmin;
153: }
154:
155: # Timing Condition
156: #-----
157:
158: TestCondition Func_Timing_SDR_Scan
159: {
160:     TestConditionGroup = wireModel_Func_SDR_Scan_Timings;
161: }
162: TestCondition Func_Timing_SDR_Alpg

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163: {
164:     TestConditionGroup = wireModel_Func_SDR_Alpg_Timings;
165: }
166:
167: # Pin Open Group
168: #-----
169: TestCondition Pin_5_8_OPEN
170: {
171:     TestConditionGroup = wireModel_Func_Pin_Open;
172: }
173:
174: # Test condition for Idd test
175: #-----
176: TestCondition Idd_Static_Function_Min
177: {
178:     TestConditionGroup = wireModel_Idd_Static_Function;
179:     Selector = min;
180: }
181: TestCondition Idd_Static_DCParams_Min
182: {
183:     TestConditionGroup = wireModel_Idd_TraceMode_DCParam;
184:     Selector = min;
185: }
186:
187: #####
Tests for Datalog Setup
188: Test DatalogSetupTest DatalogSetup
189: {
190:     DatalogSetupFileName = "DatalogStreamSetup.dls";
191:     DatalogSetupFileName = "FuncDatalogSetup.dls";
192: }
193:
194: #####
Tests for DC
195: Test DCParametricPowerSupplyTest DiagPB_Vdd_Short
196: {
197:     TestConditionParam= Idd_Short_DCParams;
198:     TestConditionParam= Idd_Short_Levels;
199:     PowerSupply= "VDD";
200:     SettlingTimePreMeasure= "3mS";
201:     SettlingTimePostMeasure= "0mS";
202: }
203: Test DCParametricPMUTest DiagPB_Contact_Open
204: {
205:     TestConditionParam= Contact_Open_Levels;
206:     TestConditionParam= Contact_Open_DCParams;
207:     MeasurementPin= "allpins";
208:     PMURelayControl= "On";
209:     MeasMode= "Simultaneous";
210:     SettlingTimePreMeasure= "3mS";
211:     SettlingTimePostMeasure= "0mS";
212: }
213:
214: #

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215: # Declare a FunctionalTest. "FunctionalTest" refers to a C++
216: # test class that runs the test, and returns a 0, 1 or 2 as
217: # a Result. The Test Condition Group TCG1 is selected with
218: # the "min" selector by referring to the TC1Min TestCondition.
219: #
220: # Note that OTPL can compile this because of the imported
221: # FunctionalTest.ph file.
222: #
223: #####
Tests for Function
224: Test FunctionalTest DiagPBFunctionalTestMin
225: {
226:     PListParam = DiagPBPAT;
227:     TestConditionParam = TC1Min;
228: }
229:
230: Test FunctionalTest DiagPBFunctionalTestMax
231: {
232:     PListParam = DiagPBPAT;
233:     TestConditionParam = TC1Max;
234: }
235:
236: Test FunctionalTest DiagPBFunctionalTestTyp
237: {
238:     PListParam = DiagPBPAT;
239:     TestConditionParam = TC1Typ;
240: }
241:
242: #####
Tests for Search
243: Test SearchTest Margin
244: {
245:     PListParam = DiagPBPAT;
246:     TestConditionParam = TC1LevelMin;
247:     TestConditionParam = TC1TimingMax;
248:     Algorithm = "margin";
249:     SearchVarParam = ",TC1TimingMax,tStrbH,0nS,10nS,10";
250: }
251:
252: Test SearchTest Shmoo
253: {
254:     PListParam = DiagPBPAT;
255:     TestConditionParam = TC1LevelMin;
256:     TestConditionParam = TC1TimingMax;
257:     Algorithm = "shmoo";
258:     SearchVarParam = "x,TC1TimingMax,tStrbH,0nS,10nS,10";
259:     SearchVarParam = "y,TC1LevelMin,voh,1V,0.5V,12";
260:     DebugMode = 0;
261: }
262:
263: #####
Tests for DC
264: Test DCParametricPMUTest DiagPB_Leakage_Low
265: {

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266:   TestConditionParam= Input_Leakage_Low_Levels;
267:   TestConditionParam= Input_Leakage_Low_DCParams;
268:   MeasurementPin= "inpins";
269:   PMURelayControl= "On";
270:   MeasMode= "Serial";
271:   SettlingTimePreMeasure= "3mS";
272:   SettlingTimePostMeasure= "0mS";
273: }
274:
275: Test DCParmetricPowerSupplyTest DiagPB_Idd_Static_Max
276: {
277:   TestConditionParam= Idd_Static_DCParams_Max;
278:   TestConditionParam= Idd_Static_Levels_Max;
279:   PowerSupply= "VDD";
280:   PinRelay= "Open";
281:   SettlingTimePreMeasure= "3mS";
282:   SettlingTimePostMeasure= "0mS";
283: }
284:
285: #####
Tests for SCAN
286:
287: Test FunctionalTest DiagPB_Func_SCAN_VT_Min
288: {
289:   PListParam= wireModel_PList_ScanTiming;
290:   TestConditionParam= Func_Min_Dps;
291:   TestConditionParam= Func_Min_Sig_VT;
292:   TestConditionParam= Func_Timing_SDR_Scan;
293: }
294:
295: #####
Tests for ALPG
296: Test FunctionalTest DiagPB_Func_ALPG_VT_Min
297: {
298:   PListParam= wireModel_PList_AlpgTiming;
299:   TestConditionParam= Func_Min_Dps;
300:   TestConditionParam= Func_Min_Sig_VT;
301:   TestConditionParam= Pin_5_8_OPEN;
302:   TestConditionParam= Func_Timing_SDR_Alpg;
303: }
304:
305: #####
Test for Module Trigger
306: Test DCParmetricPowerSupplyTest DiagPB_Idd_with_ModuleTrigger
307: {
308:   TestConditionParam= Idd_Static_Function_Min;
309:   TestConditionParam= Idd_Static_DCParams_Min;
310:   PListParam = wireModel_fixedCycle;
311:   PowerSupply= "VDD";
312:   ModuleTrigger= "PMDTR2,0xf";
313: }
314:
315: EndSequence
316: {

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317:     RoffSeq
318: }
319:
320: # Counters
321: Counters {PassCount, FailCount}
322:
323:
324: # FlowMain is the main flow.
325: Flow FlowMain
326: {
327:     #
328:     # The first declared flow is the initial flow to be
329:     # executed. It goes to FlowMain_Max on success, and
330:     # returns 1 on failure.
331:
332:     FlowItem DatalogSetupFlow DatalogSetup
333:     {
334:         Result 0
335:         {
336:             Property PassFail = "Pass";
337:             GoTo FlowMain_Vdd_Short;
338:         }
339:     }
340:     FlowItem FlowMain_Vdd_Short DiagPB_Vdd_Short
341:     {
342:         Result 0
343:         {
344:             Property PassFail = "Pass";
345:             IncrementCounters PassCount;
346:             GoTo FlowMain_Open;
347:         }
348:         Result 1
349:         {
350:             Property PassFail = "Fail";
351:             IncrementCounters FailCount;
352:             SetBin SoftBins.FailVddShortTest;
353:             GoTo FlowMain_Open;
354:         }
355:     }
356:     FlowItem FlowMain_Open DiagPB_Contact_Open
357:     {
358:         Result 0
359:         {
360:             Property PassFail = "Pass";
361:             IncrementCounters PassCount;
362:             GoTo FlowMain_IIL;
363:         }
364:         Result 1
365:         {
366:             Property PassFail = "Fail";
367:             IncrementCounters FailCount;
368:             SetBin SoftBins.FailOpenTest;
369:             GoTo FlowMain_IIL;
370:         }

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371: }
372: FlowItem FlowMain_IIL DiagPB_Leakage_Low
373: {
374:     Result 0
375:     {
376:         Property PassFail = "Pass";
377:         IncrementCounters PassCount;
378:         GoTo FlowMain_Min;
379:     }
380:     Result 1
381:     {
382:         Property PassFail = "Fail";
383:         IncrementCounters FailCount;
384:         SetBin SoftBins.FailLeakageL;
385:         GoTo FlowMain_Min;
386:     }
387: }
388: FlowItem FlowMain_Min DiagPBFunctionalTestMin
389: {
390:     Result 0
391:     {
392:         Property PassFail = "Pass";
393:         IncrementCounters PassCount;
394:         GoTo FlowMain_Max;
395:     }
396:
397:     Result 1
398:     {
399:         Property PassFail = "Fail";
400:         IncrementCounters FailCount;
401:         SetBin SoftBins.FailCache3GHz;
402:         Return 1;
403:     }
404: }
405: FlowItem FlowMain_Max DiagPBFunctionalTestMax
406: {
407:     Result 0
408:     {
409:         Property PassFail = "Pass";
410:         IncrementCounters PassCount;
411:         GoTo FlowMain_Typ;
412:     }
413:
414:     Result 1
415:     {
416:         Property PassFail = "Fail";
417:         IncrementCounters FailCount;
418:         SetBin SoftBins.FailSBFT3GHz;
419:         Return 1;
420:     }
421: }
422: FlowItem FlowMain_Typ DiagPBFunctionalTestTyp
423: {
424:     Result 0

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425:     {
426:         Property PassFail = "Pass";
427:         IncrementCounters PassCount;
428:         GoTo MarginFlow;
429:     }
430:
431:     Result 1
432:     {
433:         Property PassFail = "Fail";
434:         IncrementCounters FailCount;
435:         SetBin SoftBins.FailLeakage3GHz;
436:         Return 1;
437:     }
438: }
439: FlowItem MarginFlow Margin
440: {
441:     Result 0
442:     {
443:         Property PassFail = "Pass";
444:         GoTo ShmooFlow;
445:     }
446: }
447: FlowItem ShmooFlow Shmoo
448: {
449:     Result 0
450:     {
451:         Property PassFail = "Pass";
452:         GoTo FlowMain_Idd_Static_Max;
453:     }
454: }
455: FlowItem FlowMain_Idd_Static_Max DiagPB_Idd_Static_Max
456: {
457:     Result 0
458:     {
459:         Property PassFail = "Pass";
460:         IncrementCounters PassCount;
461:         GoTo FlowMain_Func_S_SCAN_Min;
462:     }
463:
464:     Result 1
465:     {
466:         Property PassFail = "Fail";
467:         IncrementCounters FailCount;
468:         SetBin SoftBins.FailIddMax;
469:         GoTo FlowMain_Func_S_SCAN_Min;
470:     }
471: }
472: FlowItem FlowMain_Func_S_SCAN_Min DiagPB_Func_SCAN_VT_Min
473: {
474:     Result 0
475:     {
476:         Property PassFail = "Pass";
477:         IncrementCounters PassCount;
478:         GoTo FlowMain_Func_S_ALPG_Min;

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479:     }
480:     Result 1
481:     {
482:         Property PassFail = "Fail";
483:         IncrementCounters FailCount;
484:         SetBin SoftBins.FailFuncMin;
485:         Return 1;
486:     }
487: }
488: FlowItem FlowMain_Func_S_ALPG_Min DiagPB_Func_ALPG_VT_Min
489: {
490:     Result 0
491:     {
492:         Property PassFail = "Pass";
493:         IncrementCounters PassCount;
494:         GoTo FlowMain_Idd_with_ModuleTrigger;
495:     }
496:     Result 1
497:     {
498:         Property PassFail = "Fail";
499:         IncrementCounters FailCount;
500:         SetBin SoftBins.FailFuncMin;
501:         Return 1;
502:     }
503: }
504: FlowItem FlowMain_Idd_with_ModuleTrigger DiagPB_Idd_with_ModuleTrigger
505: {
506:     Result 0
507:     {
508:         Property PassFail = "Pass";
509:         IncrementCounters PassCount;
510:         SetBin SoftBins.PassAll3GHz;
511:         Return 0;
512:     }
513:     Result 1
514:     {
515:         Property PassFail = "Fail";
516:         IncrementCounters FailCount;
517:         SetBin SoftBins.FailIddMin;
518:         Return 1;
519:     }
520: }
521: }
522:
523: # Specifies some special flows, including the flow that
524: # is the main flow. This can be used to specify other
525: # flows that can be launched when a test starts, etc.
526: FlowDefs
527: {
528:     MainFlow = FlowMain;
529: }

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